

<b>Notice of References Cited</b>	Application/Control No. 10/595,077		Applicant(s)/Patent Under Reexamination YAMAZAWA ET AL.	
	Examiner Mary Lynn F. Theisen		Art Unit 1791	Page 1 of 1

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*	B	US-7,435,367	10-2008	Oriakhi, Christopher	264/113
*	C	US-7,455,804	11-2008	Patel et al.	264/460
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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